

In the Claims

Claim 1 (original): A method of forming a semiconductor construction, comprising:

- forming a mass over a semiconductor substrate;
- forming first and second layers over the mass, and over a region of the substrate proximate the mass;
- removing the first and second layers from over the mass while leaving portions of the first and second layers over the region proximate the mass;
- etching the first layer with an etch selective for the first layer relative to the second layer to remove at least some of the first layer from under the second layer and thereby form a channel over the region proximate the mass; and
- forming a material within the channel.

Claim 2 (original): The method of claim 1 wherein the mass comprises a memory bit which includes a first magnetic layer, a second magnetic layer, and a non-magnetic layer between the first and second magnetic layers.

Claim 3 (original): The method of claim 1 wherein the removing the first and second layers from over the mass comprises chemical-mechanical polishing of the first and second layers.

Claim 4 (original): The method of claim 1 wherein the first layer comprises silicon dioxide and the second layer comprises silicon nitride.

Claim 5 (original): The method of claim 1 wherein the first layer comprises silicon nitride and the second layer comprises silicon dioxide.

Claim 6 (original): The method of claim 1 wherein the second layer comprises silicon carbide and the first layer does not comprise silicon carbide.

Claim 7 (original): The method of claim 1 wherein the second layer consists essentially of one or both of silicon and carbon; and wherein the first layer consists essentially of silicon and one or both of nitrogen and oxygen.

Claim 8 (original): The method of claim 1 wherein the second layer consists essentially of silicon and one or both of nitrogen and oxygen; and wherein the first layer comprises carbon.

Claim 9 (original): The method of claim 1 wherein the material formed within the channel is a soft magnetic material comprising one or more of nickel, iron and copper.

Claim 10 (original): The method of claim 1 wherein the material formed within the channel consists essentially of mu-metal.

Claims 11-77 (cancelled).